

INTRODUCTION

- 1. The contents is subject to change without notice. Please exchange the specification sheets regarding the product's warranty.
- 2. This sheet is not intended to guarantee or provide an approval of implementation of industrial patents.
- 3. We have prepared this sheet as carefully as possible. If you find it incomplete or unsatisfactory in any respect, We would welcome your comments.

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Product No. / Model

The product No. of this crystal unit is Q22FA1280004300. The model is FA-128.

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[1] Absolute maximum ratings

No.	Parameter	Rating value	Note	
1	Storage temperature	-40 °C to +125 °C	Suppose to be within CI std. at +25 °C \pm 3 °C	

[2] Operating range

		~	Value			
No. Parameter		Symbol	Min.	Тур.	Max.	
1	Operating temperature	T_use	-40 °C		+85 °C	
2	Drive level	DL	10 µW		100 µW	

[3] Electrical characteristics

No.	Parameter	Symbol	Standard	Conditions
1	Nominal frequency	fo	32 MHz	Fundamental
2	Frequency tolerance	f_tol	$\pm 10 \times 10^{-6}$	CL= 8 pF T_use = +25 °C±3 °C Drive level : 100 μW Not include aging
3	Motional resistance	R1	60 Ω Max.	π circuit JIS C6701 Drive level : 100 μW T_use= -40 °C to +85 °C
4	Shunt capacitance	C0	3.0 pF Max.	
5	Frequency versus temperature characteristics	f_tem	$\pm 20 \times 10^{-6}$	$T_use = -40 \text{ °C to } +85 \text{ °C}$ (Ref. at +25 °C±3 °C) Drive level : 100 μ W
6	Isolation resistance	IR	500 MΩ Min.	DC 100V × 60 sec. Between each terminals
7	Aging	f_age	$\pm 1 \times 10^{-6}$ /year	$T_use = +25 \text{ °C} \pm 3 \text{ °C}$ Drive level : 100 µW

[4] Environmental and mechanical characteristics

Item No.3 to No.6 shall be tested after following pre conditioning.

(The	company evaluation condition . v	ve evaluate it by the following ex			
No	Item	Value *1 *2	Test Conditions		
110.	nem	$\Delta f / f [1 \times 10^{-6}]$	Test Conditions		
1	Drop	*3 ±2	150 g dummy Jig (SE Standard) drop		
			from 1500 mm height on the Concrete 6		
			directions 10 times		
2	Vibration	*3 ±2	10 Hz to 55 Hz amplitude 0.75 mm		
			55 Hz to 500 Hz acceleration 98 m/s ²		
			$10 \text{ Hz} \rightarrow 500 \text{ Hz} \rightarrow 10 \text{ Hz} 15 \text{ min./cycle}$		
			6 h (2 hours, 3 directions)		
3	High temperature storage	*3 ±2	+85 °C × 1 000 h		
4	Low temperature storage	*3 ±2	-40 °C × 1 000 h		
5	Temperature cycle	*3 ±2	$-40 \ ^{\circ}C \leftrightarrow +85 \ ^{\circ}C$		
			30 minutes at each temp. 100 cycle		
6	Temperature humidity	*3 ±2	+85 °C × 85 %RH × 1 000 h		
	storage				
7	Resistance to soldering heat	± 2	For convention reflow soldering furnace		
			(3 times)		
8	Substrate bending	No peeling-off at a soldered	Bend width reaches 3 mm and hold for		
		part	5 s \pm 1 s \times 1 time Ref. IEC 60068-2-21		
9	Shear	No peeling-off at a soldered	10 N press for 10 s \pm 1 s		
		part	Ref. IEC 60068-2-21		
10	Pull – off	No peeling-off at a soldered	10 N press for 10 s \pm 1 s		
		part	Ref. IEC 60068-2-21		
11	Solder ability	Terminals must be 95 %	Dip termination into solder bath at		
		covered	$+235$ °C ± 10 °C for 5 s		

Pre conditioning : Test crystal must be leaving in room temperature for 24 h after reflow \times 3. /**T**1 J:4: Wo valuate it by the followi 1... lucti ination ita nd e aminati

< Notes >

1. *1 each test done independently.

*2 measuring 2 h to $2\hat{4}$ h later leaving in room temperature after each test. 2.

*3 Item No.1 to No.6 shall be tested after following pre conditioning. 3.

Item No.1 to No.11 resistance at before above tests should be less than ± 20 % or less than $\pm 10 \Omega$. 4.

With fresh solder.

(Using Rosin Flux)

Pre conditioning : Test crystal must be leaving in room temperature for 24h after reflow \times 3. 5.

Reflow condition (follow to IPC / JEDEC J-STD-020C)



[5] Dimensions and Circuit



[6] Recommended soldering pattern and Marking layout



[7] Notes

- 1. Max three (3) times re-flow is allowed. Its recommended to manually solder when not enough/no solder detected.(Using soldering iron at +350 °C × within 5 seconds)
- 2. Patterning on a board should follow our company recommended pattern.
- 3. Applying excessive excitation force to the crystal unit may cause deterioration damage.
- 4. Start up time of oscillation may be increased or no oscillation may occur unless adequate negative resistance is allocated in the oscillation circuit In order to avoid this, please provide enough negative resistance to the circuit design.

How to check the negative resistance



- 5. It is recommended to do patterning to the oscillator as short as possible. Abnormal oscillation may happened if the line is too long.
- 6. To avoid malfunction, no pattern across or near the crystal unit is allowed.
- 7. Few data or readings taken at user side may be different from our company's data. Confirmation of the different value is necessary before application.
- Too much exciting shock or vibration may cause deterioration on damage. The product may damage depends on the condition such as a shock in assembly machinery. Please check your process condition in advance to minimize and maintain the shock level.
- 9. This product may be affected to ultrasonic cleaning. It is depends on the cleaning conditions (Cleaning machine type/power/time/content/position etc.). The warranty will not cover any damage due to this type of usage. Check conditions prior to use.
- 10. Condensation may occur when used/stored under high humidity condition. Please take precautions to prevent condensation.
- 11. Please refer to packing specification for the storage method and packing standard.

TAPING SPECIFICATION

1. APPLICATION

This document is applicable to FA-128

2. CONTENTS

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- (1) angle : cover tape during peel off and the direction of unreeling shall be 165° to 180° .
- \bigcirc peel speed : 300 mm / min.
- ③ strength : 0.1 to 1 N.

P. 2

[2] Inner Carton

a) Packing to antistatic bag



b) Packing to inner carton



[3] Shipping Carton



[4] Marking

- (1) Reel marking
 - Reel marking shall consist of :
 - 1) Parts name
 - 2) Quantity
 - 3) Manufacturing Date or symbol
 - 4) Manufacturer's Date or symbol
 - 5) Others (if necessary)
- (2) Inner carton marking
 - Same as Reel marking.
- (3) Shipping carton marking
 - Shipping carton marking shall consist of :
 - 1) Parts name
 - 2) Quantity

[5] Quantity

• 3 000 pcs./reel

[6] Storage environment

- (1) Before open the packing, we recommend to keep less than +30 °C and 85 %RH of Humidity, and to use it less than 6 months after delivery.
- (2) We recommend to open Package in immediately before use. After open Package, We recommend to keeps less than 6 month. No need dry air before soldering work if it is less than temperature +30 °C, 85 humidity %RH.
- (3) Not to expose the sun.
- (4) Not to storage with some erosive chemicals.
- (5) Nothing is allowed to put on the reel or carton to prevent mechanical damage.

[7] Handling

To handle with care to prevent the damage of tape, reel and products.

- Process Quality Control -

No. I-0502-01-AIE-5

SMD TYPE AT STRIP CRYSTAL : FA-128

12.09.26

Manufacturing process shart		No.	Section	Standard	Inspection, Control items	Inspection method	Instrument	Record
Crystal block		1	Inspecting section.	Purchasing specification	Size.	Sampling.	Measure.	In-coming inspection
7	7		(Ina / Miyazaki Plant)	Incoming inspection standard	Outer appearance.	"	Visual inspection.	data sheet.
					Inner appearance.	"	Visual inspection.	
R R	In-coming inspection	1'	Inspecting section.	11	Size.	Sampling.	Comparator.	//
	T		(Ina / Thailand / Malaysia Plant)		Outer appearance.		Micro scope.	
(a)	Wafer cutting	2	Inspecting section.	Manufacturing instruction sheet	Cut angle.	Sampling.	X-ray raido grafic.	Process data sheet.
			(Ina / Miyazaki Plant)		Wafer thickness.		Comparator.	
Ceramic base	3 Wafer lapping	3	Producing section.	11	Frequency.	Sampling.	Frequency counter.	11
(1) In-coming			(Ina / Miyazaki Plant)		Wafer thickness.		Comparator.	
inspection @	Photo process	4	Producing section.	11	Size.	Sampling.	Comparator.	11
			(Ina / Miyazaki Plant)		Frequency.		Frequency counter.	
					Outer appearance.		Micro scope.	
Lid	Mounting	5	Producing section.	11	Outer appearance.	All insprcion.	Micro scope.	"
∇			(Ina / Thailand / Malaysia Plant / GKL)					
In-coming	Frequency adjustment	6	Producing section.	"	Frequency.	Sampling.	Network analyzer.	"
(1) inspection			(Ina / Thailand / Malaysia Plant / GKL)			1 0	,	
Y	4	7	Producing section.	"	Outer appearance.	Sampling.	Micro scope.	//
G	7) Welding		(Ina / Thailand / Malaysia Plant / GKL)			- F 5		
		8	Producing section.	"	Airtightness check.	All insprcion.	Leak tester.	//
	3 Leak test		(Ina / Thailand / Malaysia Plant / GKL)		Ũ			
	Ĭ	9	Producing section.	"	Outer appearance.	Sampling.	Micro scope.	"
(5) D Marking		(Ina / Thailand / Malaysia Plant / GKL)			1 0		
		10	Producing section.	"	Crystal impedance.	All insprcion.	Inspectional machine.	"
4	0 Characteristic inspection		(Ina / Thailand / Malaysia Plant / GKL)		Frequency.			
	Ť ·		- · ·		Insulation resistance.			
					Temp. characteristic.	Sampling.		
						1 0		
4	1 Out-going inspection	11	Inspecting section.	Out-going inspection standard	Crystal impedance.	Sampling.	Inspection M/C.	Out-going inspection
			(Ina / Thailand / Malaysia Plant / GKL)	0 0 1	Frequency.	"		data sheet.
					Insulation resistance.			
					Outer appearance.		Micro scope.	
đ		12	Producing section.	Manufacturing instruction sheet	Tape-peel strength.	Sampling.	Peelinf force tester.	Process data sheet.
			(Ina / Thailand / Malaysia Plant / GKL)	5		1 0		
đ	3 Packing	13	Product control section.	Manufacturing instruction sheet	Address.			Delivery slip.
	3		(Ina / Thailand / Malaysia Plant)	Packing instruction sheet	Quantity.	_	_	
			· · · · · · · · · · · · · · · · · · ·					

No.: A-0502-AE-1



RELIABILITY TEST DATA Product Name : FA-128

The Company evaluation condition

We evaluate environmental and mechanical characteristics by the following test condition .

			VALUE *1 *2	TEST	FAIL
No.	ITEM	TEST CONDITIONS	$\Delta f / f$	Qty	Qty
			$[1 \times 10^{-6}]$	[n]	[n]
1	Drop	150 g dummy Jig (Epsontoyocom Standard) drop from 1 500 mm height on the Concrete 6 directions 10 times	*3 ± 2	22	0
2	Vibration	10 Hz to 55 Hz amplitude 0.75 mm 55 Hz to 500 Hz acceleration 98 m/s ² 10 Hz \rightarrow 500 Hz \rightarrow 10 Hz 15 min / cycle 6 h (2 h × 3 directions)	*3 ± 2	22	0
3	High temperature storage	+85 °C × 1 000 h	*3 ± 2	22	0
4	Low temperature storage	-40 °C × 1 000 h	*3 ± 2	22	0
5	Temperature cycle	-40 °C \Leftrightarrow + 85 °C 30 min at each temp. 100 cycles	*3 ± 2	22	0
6	Temperature humidity storage	+85 °C × 85 %RH × 1 000 h	*3 ± 2	22	0
7	Resistance to soldering heat	For convention reflow soldering furnace (3 times)	± 2	22	0
8	Substrate bending	Bend width reaches 3.0 mm and hold for 5 s \pm 1 s \times 1 time Ref. IEC 60068-2-21	No peeling - off at a solder part	11	0
9	Shear	10 N press for 10 s ± 1 s Ref. IEC 60068-2-21	No peeling - off at a solder part	11	0
10	Pull - off	10 N press for 10 s ± 1 s Ref. IEC 60068-2-21	No peeling - off at a solder part	11	0
11	Solderability	Dip termination into solder bath at $+235^{\circ}C \pm 10^{\circ}C$ for 5 s (Using Rosin Flux)	Termination must be 95 % covered with fresh solder	11	0

Notes

1. *1 Each test done independently.

2. *2 Measuring 2 h to 24 h later leaving in room temperature after each test.

3. *3 Measuring 24 h later leaving in room temperature after each test.

- 1. Reflow 3 times
- 2. Initial value shall be after 24h at room temperature.

4. Shift series resistance at before above tests should be less than ± 20 % or less than $\pm 10 \Omega$.



Product Name : FA-128



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